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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Lidu Huang, et al.
Serial No.: 10/808,665
Filed: March 24, 2004
For: *Methods and Apparatuses for Measuring the
Refractive Index and Other Optical Properties
of Liquids, Gels and Solids*
Art Group Unit: 2877
Examiner: Unknown
Attorney Docket: 02EK-105598

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MAILING/TRANSMISSION
(37 C.F.R. § 1.8A)**

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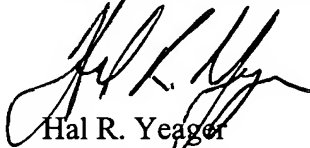
The citation listed on the enclosed PTO-1449 Form is submitted under 37 C.F.R. §§1.97 and 1.98, and in compliance with the duty of disclosure as defined in 37 C.F.R. §1.56.

The Examiner is requested to make this citation officially of record in the application. This Information Disclosure Statement is being submitted before receipt of the first Office Action for the above-identified application, therefore, pursuant to 37 C.F.R. §1.97, no fee or certification is required.

This Information Disclosure Statement is not to be construed as a representation or admission that any of the listed citations, by itself or in combination with other information, is material to patentability, is, in fact, prior art, or establishes or a *prima facie* case of unpatentability of any claim in the above-identified application. Additionally, this Information

Disclosure Statement is not to be construed as a representation that a further search of the art has been made by Applicants, or that additional information relevant to the examination of this application does not exist unbeknownst to Applicants.

Respectfully submitted,

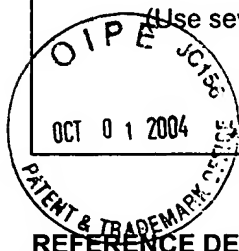


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September 29, 2004

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FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT(S)' INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO. 02EK-105598	SERIAL NO. 10/808,665
	APPLICANT: Lidu Huang, et al.	
	FILING DATE: March 24, 2004	GROUP ART UNIT: 2877



REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAM'R INITIAL		DOCUMENT NUMBER	DATE	NAME	Class	Subclass	Filing Date If Appropriate
	A						
	A						
	A						

FOREIGN PATENT DOCUMENTS

EXAM'R INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	Subclass	TRANSLAT'N	
							yes	no
	B							
	B							

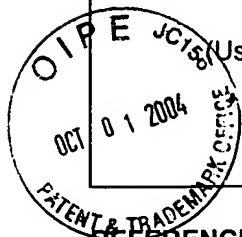
OTHER ART (Include Author, Title, Date, Pertinent Pages, Etc.)

C7	A. L. Glebov, L. Huang, S. Aoki, M. G. Lee and K. Yokochi, "Two dimensional microlens arrays in silica-on-silican planar lightwave circuit technology", Journal of Microlithography, Microfabrication, & Microsystems, vol 2, no. 4, pp. 309-318, 2003
C8	Metricon Corp., "Model 2010 Prism Coupler Application Notes Measuring Index Anisotropy of Free-Standing Polymer Films," www.metricon.com/appli6.htm , 6/29/2004
C9	Brother Gregory Investigates, "Measuring Refractive Index," www.brooklyn.cuny.edu/bc/ahp/CellBio/RefIndex/RI.Main.html , 6/30/2004
C10	
C11	
C12	

EXAMINER	DATE CONSIDERED
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U.S. PATENT DOCUMENTS

EXAM'R INITIAL		DOCUMENT NUMBER	DATE	NAME	Class	Subclass	Filing Date If Appropriate
	A1	6,504,966	01/07/2003	Kato et al.	385	16	
	A2						
	A3						
	A4						

FOREIGN PATENT DOCUMENTS

EXAM'R INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	Subclass	TRANSLAT'N	
							yes	no
	B							
	B							

OTHER ART (Include Author, Title, Date, Pertinent Pages, Etc.)

	C1	"Silica Integrated Optical Circuits", edited by H. M. Presby, Section 2 "Fabrication", SPIE Milestone Series, vol. MS 125, pp. 43-149, 1996
	C2	T. Fukano and I. Yamoguchi, "Simultaneous measurement of thickness and refractive indices of multilayers by a low-coherence confocal interference microscope", Opt. Lett., vol. 21, pp. 1942-1944, 1996
	C3	G. J. Veldhuis, L.E. W. van Veen and P. V. Lambeck, "Integrated optical refractometer based on waveguide bend loss", IEEE J. Lightwave Technol., vl. 17, pp. 857-864, 1999
	C4	D. C. Yin and Y. Inatomi, "Measurement of refractive index of GaP crystal over a large temperature range using interferometry", Cryst. Res. Technol., vol. 35, pp. 221-228, 2000
	C5	T. Dennis, E. M. Gill and S. L. Gilbert, "Interferometric measurement of refractive-index change in photosensitive glass", Appl. Optics, vol. 40, pp. 1663-1667, 2001
	C6	O. M. Efimov, L. B. Glebov and H. P. Andre, "Measurement of the induced refractive index in a photothermorefractive glass by a liquid-cell shearing interferometer", Appl. Optics, vol. 41, pp.1864-1870, 2002

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